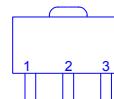
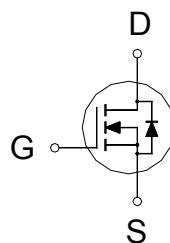


NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
PA110BC
SOT-89
Halogen-Free & Lead-Free
PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
100V	110mΩ	4A



1. GATE
-
2. DRAIN
-
3. SOURCE

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS		UNITS
Drain-Source Voltage		V_{DS}	100		V
Gate-Source Voltage		V_{GS}	± 20		V
Continuous Drain Current	$T_A = 25^\circ\text{C}$	I_D	4		A
	$T_A = 100^\circ\text{C}$		3.5		
Pulsed Drain Current ¹		I_{DM}	15		
Avalanche Current		I_{AS}	4.8		
Avalanche Energy	$L = 1\text{mH}$	E_{AS}	11.5		mJ
Power Dissipation ³	$T_A = 25^\circ\text{C}$	P_D	3.9		W
	$T_A = 100^\circ\text{C}$		2.5		
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150		°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE		SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	$t \leq 10\text{s}$	$R_{\theta JA}$		32	°C / W
Junction-to-Ambient ²	Steady-State	$R_{\theta JA}$		63	
Junction-to-Case		$R_{\theta JC}$		20	

¹Pulse width limited by maximum junction temperature.²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$.³The Power dissipation is based on $R_{\theta JA} t \leq 10\text{s}$ value.**ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	100			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1	1.8	3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			± 100	nA

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Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 80V, V_{GS} = 0V$			1	μA
		$V_{DS} = 80V, V_{GS} = 0V, T_J = 125^\circ C$			10	
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 4.5V, I_D = 4A$		86	120	$m\Omega$
		$V_{GS} = 10V, I_D = 4A$		81	110	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 5V, I_D = 4A$		22		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		573		pF
Output Capacitance	C_{oss}			58		
Reverse Transfer Capacitance	C_{rss}			32		
Gate Resistance	R_g	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$		1.5		Ω
Total Gate Charge ²	$Q_{g(VGS=10V)}$	$V_{DS} = 50V, I_D = 4A$		13.6		nC
	$Q_{g(VGS=4.5V)}$			8		
Gate-Source Charge ²	Q_{gs}			2		
Gate-Drain Charge ²	Q_{gd}			4.6		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DS} = 50V$ $I_D \approx 4A, V_{GS} = 10V, R_{GS} = 6\Omega$		16		nS
Rise Time ²	t_r			5		
Turn-Off Delay Time ²	$t_{d(off)}$			35		
Fall Time ²	t_f			10		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current	I_S				2.8	A
Forward Voltage ¹	V_{SD}	$I_F = 4A, V_{GS} = 0V$			1.4	V
Reverse Recovery Time	t_{rr}	$I_F = 4A, dI/dt = 100 A/\mu s$		21		nS
Reverse Recovery Charge	Q_{rr}			14		nC

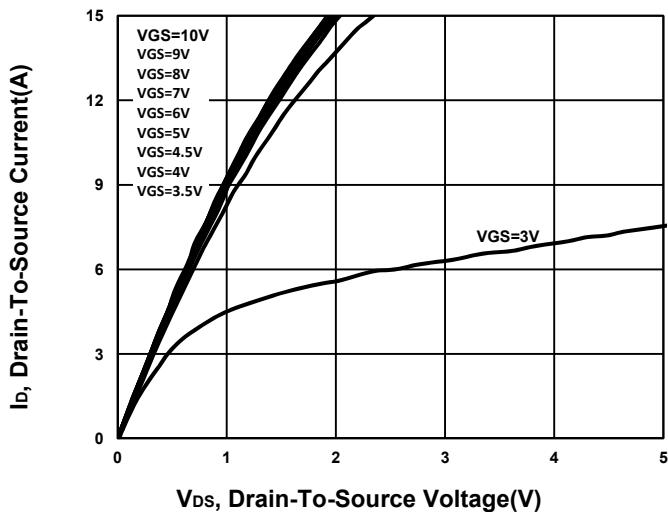
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

NIKO-SEM

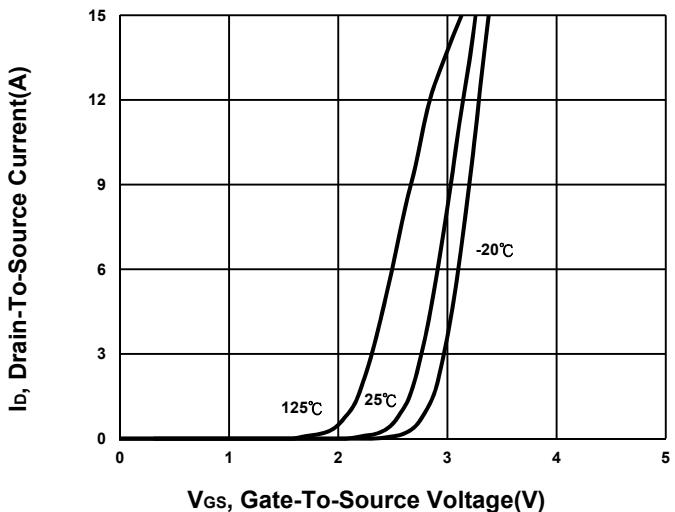
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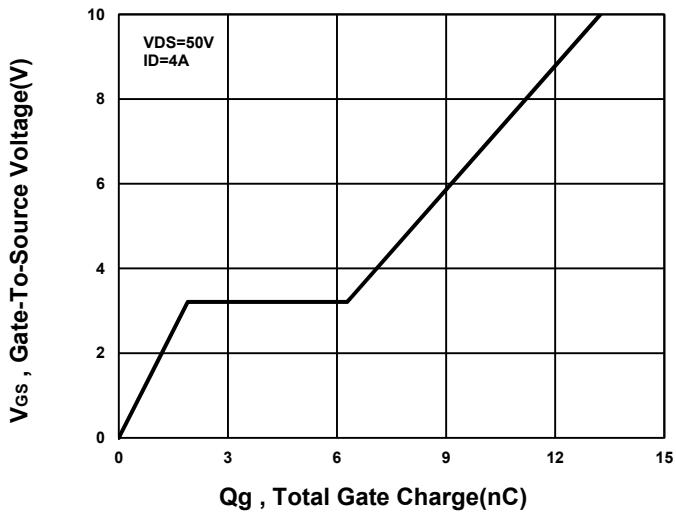
Output Characteristics



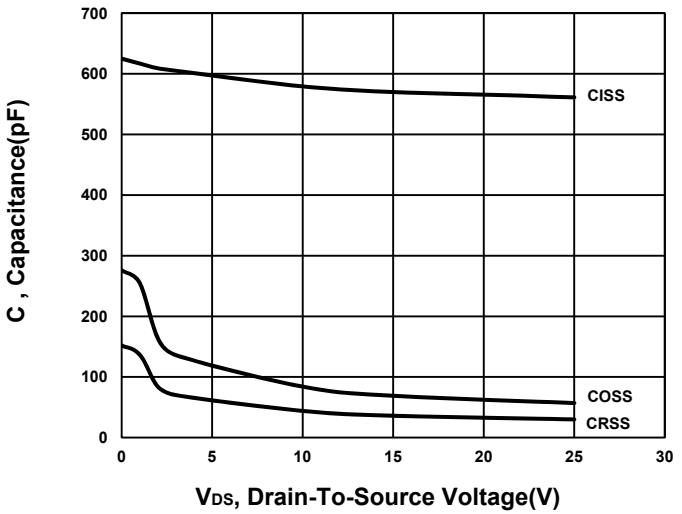
Transfer Characteristics



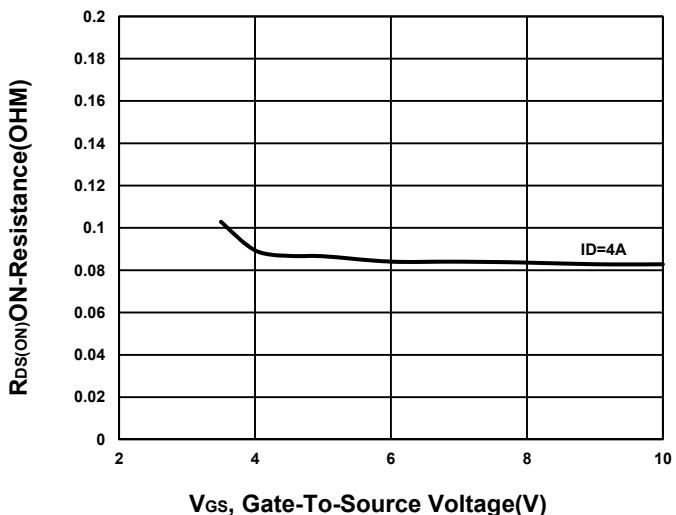
Gate charge Characteristics



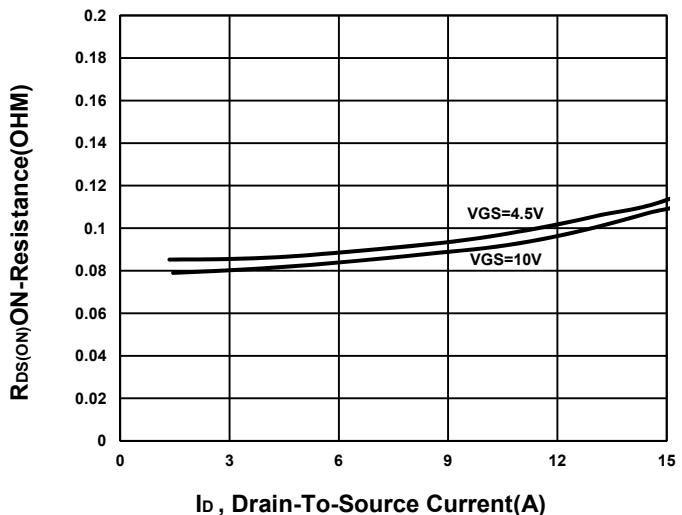
Capacitance Characteristic

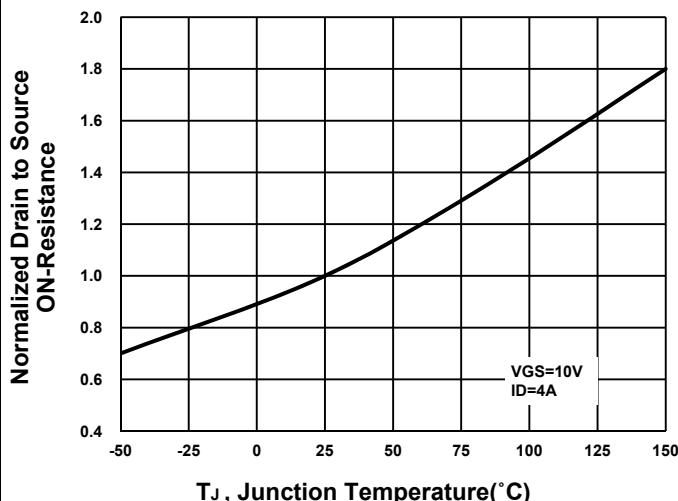
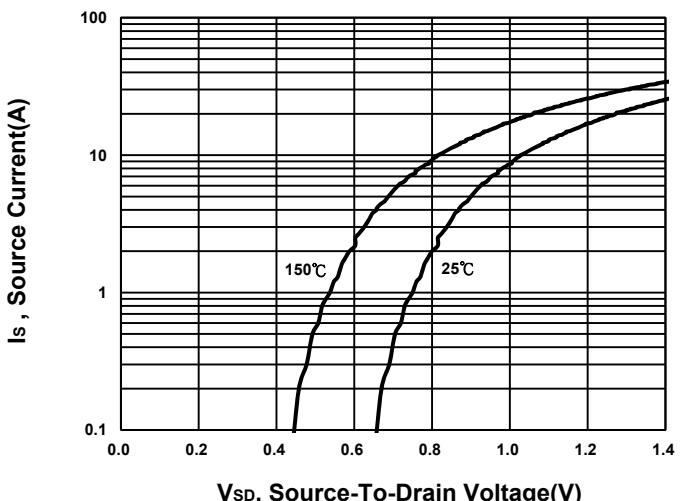
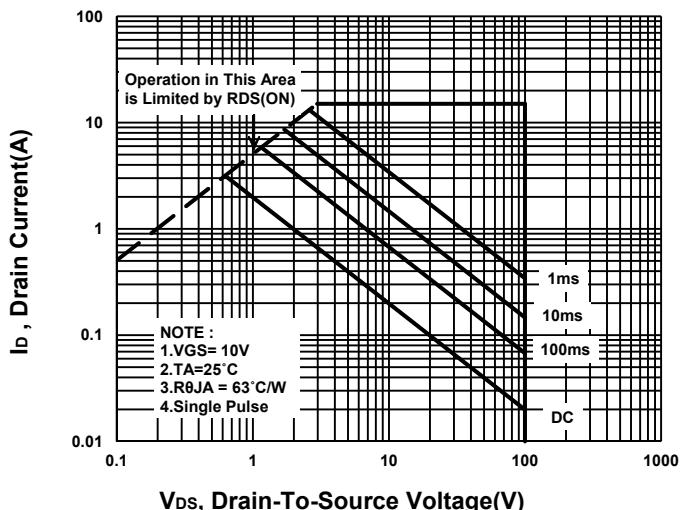
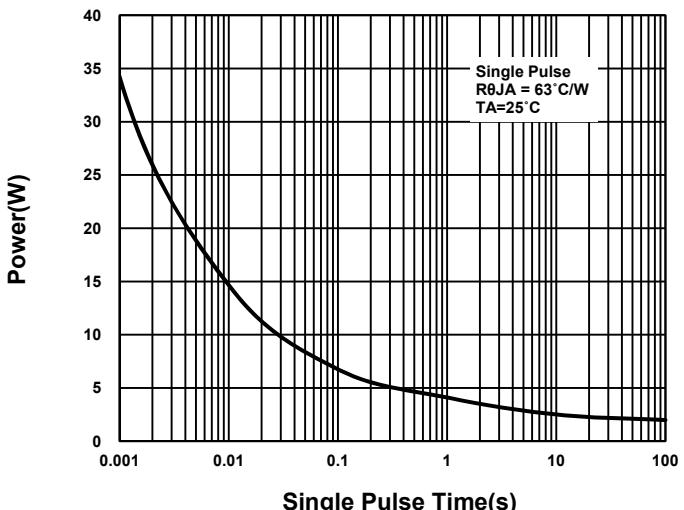


On-Resistance VS Gate-To-Source



On-Resistance VS Drain Current



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On-Resistance VS Temperature**Source-Drain Diode Forward Voltage****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**